

<b>Notice of References Cited</b>	Application/Control No. 10/015,236	Applicant(s)/Patent Under Reexamination DIETZ ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,442,390	08-2002	Sano, Fumiharu	455/450
	B	US-6,434,362	08-2002	Schier, Achim	455/45
	C	US-2003/0158741	08-2003	Nakano, Takehiko	704/503
	D	US-6,349,410	02-2002	Lortz, Victor B.	725/110
	E	US-6,115,596	09-2000	Raith et al.	455/404.2
	F	US-2002/0136384	09-2002	McCormack et al.	379/215.01
	G	US-4,268,724	05-1981	Hubbard, William	369/7
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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